## Notice of References Cited Application/Control No. 10/709,279 Examiner MUHAMMAD N. EDUN Applicant(s)/Patent Under Reexamination YANG ET AL. Page 1 of 1

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*	Α	US-2002/0094069	07-2002	Takahashi et al.	379/93.17
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	K	US-			
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## **NON-PATENT DOCUMENTS**

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